


# Micro Crack

<b>Purpose</b>	Field proven optical solution provides ultra thin micro crack defect detection capability on Silicon bare die and Integrated Passive Devices(IPD).
<b>Technology</b>	1. <b>Ultimate PVI</b> – Inspects 0.5um micro crack on wide range of package types and sizes range from 2x2mm to 120x120mm

STI Products	Ultimate PVI
 Hexa – Tray 2D & 3D Scan	